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Editors

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Contents

Part One

xv	<i>Conference Committee</i>
xvii	<i>Symposium Committees</i>
xix	<i>Introduction</i>

PLENARY PRESENTATION

6834 02	The National Ignition Facility: the world's largest optical system (Plenary Paper) [6834-188] C. J. Stolz, Lawrence Livermore National Lab. (USA)
---------	---

SESSION 1 NANO-AND MICRO-OPTICS

6834 03	Nano-glass imprinting technology for next-generation optical devices (Invited Paper) [6834-18] J. Nishii, National Institute of Advanced Industrial Science and Technology (Japan)
6834 04	Technological strategy for advanced micro- and nano-structured optical elements (Invited Paper) [6834-159] H. Kikuta, Osaka Prefecture Univ. (Japan)
6834 05	Bending insensitive optical curl cord patch cords based on Holey-fibers for FTTH (Invited Paper) [6834-01] C.-H. Jung, C.-H. Ouh, K.-S. Ryu, H.-J. Kang, Optomagic Co., Ltd. (South Korea); S.-B. Lee, Korea Institute of Science and Technology (South Korea); Y.-G. Han, Hanyang Univ. (South Korea)
6834 06	Theoretical analysis of square GRIN lens [6834-05] Z. Zhou, K. Chen, R. Zhang, Southwest Univ. of Science and Technology (China)

SESSION 2 ILLUMINATION SYSTEM DESIGN

6834 07	Backlight pattern optimization (Invited Paper) [6834-191] W. J. Cassarly, Optical Research Associates (USA)
6834 08	Polarimetry of illumination for 193-nm lithography used for the manufacture of high-end LSIs (Invited Paper) [6834-08] H. Nomura, Y. Furutono, Toshiba Corp. (Japan)
6834 09	A novel highly integrated light guide plate using micro optical technique [6834-73] P. Xu, X. Chen, J. Huang, X. Zhang, L. Wan, K. Wang, J. Liu, Shenzhen Univ. (China)

- 6834 0A **Rays propagation in optical tunnel** [6834-102]
Z. Liao, Institute of Optics and Electronics (China) and Graduate School of Chinese Academy of Sciences (China); T. Xing, Institute of Optics and Electronics (China)

SESSION 3 ASTRONOMICAL AND SPACE OPTICS

- 6834 0B **Alignment induced aberration fields of next generation telescopes (Invited Paper)** [6834-187]
K. Thompson, Optical Research Associates (USA); T. Schmid, J. Rolland, CREOL, Univ. of Central Florida (USA)
- 6834 0C **The research on electric method for testing co-phasing error (Invited Paper)** [6834-121]
W. Zhao, G. Cao, Beijing Institute of Technology (China)
- 6834 0D **Imaging analysis of optical sparse aperture systems with multiple-array configuration designs** [6834-52]
J. Zhao, D. Wang, J. Han, Z. Jiang, Y. Wan, Beijing Univ. of Technology (China); H. Guo, National Astronomical Observatories (China); S. Tao, Beijing Univ. of Technology (China)

SESSION 4 HEAD-MOUNTED DISPLAY DESIGN

- 6834 0G **Beyond the desktop: emerging technologies for supporting collaborative teams in virtual environments (Invited Paper)** [6834-193]
J. Rolland, College of Optics and Photonics, Univ. of Central Florida (USA) and Univ. of Central Florida (USA); O. Cakmakci, K.-S. Lee, College of Optics and Photonics, Univ. of Central Florida (USA); C. Fidopiastis, College of Optics and Photonics, Univ. of Central Florida (USA) and Univ. of Central Florida (USA); F. Hamza-Lup, Armstrong Atlantic State Univ. (USA); A. Santhanam, College of Optics and Photonics, Univ. of Central Florida (USA), Univ. of Central Florida (USA), Armstrong Atlantic State Univ. (USA), and MD Anderson Cancer Ctr. Orlando (USA)
- 6834 0H **Design of hybrid refractive-diffractive objective lens of head-mounted projective displays** [6834-109]
Y. Zhang, Changchun Univ. of Science and Technology (China)
- 6834 0I **Research-oriented teaching in optical design course and its function in education** [6834-155]
Z. Cen, X. Li, X. Liu, S. Deng, Zhejiang Univ. (China)

SESSION 5 COMPACT OPTICS

- 6834 0K **Optical design, fabrication, and evaluation of optical systems using free-shaped prism (Invited Paper)** [6834-131]
H. Ohde, T. Nagata, Olympus Corp. (Japan)
- 6834 0M **Design of an objective lens for optical disc systems employing a blue laser by scalar diffraction simulation** [6834-172]
N. Yamagata, S. Takeuchi, K. Yamanaka, D. Koreeda, K. Maruyama, Pentax Corp. (Japan)

- 6834 ON **Study on mathematical modeling for optical pickup virtual analyzer** [6834-153]
X. Cheng, J. Ma, S. Yan, Tsinghua Univ. (China)

SESSION 6 INTERFEROMETRY IN OPTICAL TESTING

- 6834 OO **New low-cost metrology system for mass production (Invited Paper)** [6834-23]
T. Blümel, M. Bosse, FISBA OPTIK GmbH (Germany); J. Fehse, Y. Gilliland, FISBA OPTIK AG (Switzerland); R. Kafka, R. Neubert, FISBA OPTIK GmbH (Germany); C. Zellweger, FISBA OPTIK AG (Switzerland)
- 6834 OP **A compact, high-speed, desktop turnkey measurement system for the characterization of the surface topography of spherical, aspherical, and toroidal surfaces** [6834-150]
S. D. Fantone, D. A. Imrie, J. Zhang, Optikos Corp. (USA)
- 6834 OQ **Mach-Zehnder optical interferometric polarimeter using two reference beams with different heterodyne frequency** [6834-34]
H. Liu, Y. Li, G. Cui, Y. Zhang, J. Chen, J. Xu, Q. Sun, Nankai Univ. (China)
- 6834 OR **New interferometric algorithm for the measurement of phasing errors in spherical segmented-mirrors system** [6834-25]
F. Yu, M. Hui, Y. Zhao, F. Liu, Beijing Institute of Technology (China)
- 6834 OS **Inhomogeneous radial shearing technique** [6834-164]
Z. Ghadyani, Univ. of Tehran (Iran)

SESSION 7 TESTING FOR ASPHERIC SURFACES

- 6834 OT **Study on testing larger asphericity in non-null interferometer (Invited Paper)** [6834-180]
Y. Yang, D. Liu, Y. Shen, J. Weng, Y. Zhuo, Zhejiang Univ. (China)
- 6834 OU **System optimization of radial shearing interferometer for aspheric testing** [6834-178]
D. Liu, Y. Yang, Y. Shen, J. Weng, Y. Zhuo, Zhejiang Univ. (China)

SESSION 8 NOVEL SYSTEM DESIGN

- 6834 OW **Optics for digital photography (Invited Paper)** [6834-196]
K. Lenhardt, Jos. Schneider Optische Werke GmbH (Germany)
- 6834 OY **Compact hyperspectral imaging system with a convex grating** [6834-51]
Y. Ji, W. Shen, Soochow Univ. (China)
- 6834 OZ **Design of a lens system within mobile terminal** [6834-158]
J. Liu, Huazhong Univ. of Science and Technology (China) and China Aerodynamics Research and Development Ctr. (China); J. Ding, Beijing Institute of Technology (China)
- 6834 IO **Singlet mega-pixel resolution lens** [6834-136]
C.-H. Lin, H. Y. Lin, National Taiwan Univ. (Taiwan, China); H. Chang, Fu Jen Catholic Univ. (Taiwan, China)

SESSION 9 WAVEFRONT SENSING AND CODING

- 6834 11 **High-resolution imaging of phase-distorted extended object using SPGD algorithm and deformable mirror** [6834-19]
H. Yang, Institute of Optics and Electronics (China) and Graduate Univ. of Chinese Academy of Sciences (China); X. Li, W. Jiang, Institute of Optics and Electronics (China)
- 6834 12 **Wavefront sensing** [6834-177]
M. Garcia, F. Granados, A. Cornejo, National Institute of Astrophysics, Optics and Electronics (Mexico)
- 6834 13 **Wavefront error correction with stochastic parallel gradient descent algorithm** [6834-41]
J. Liu, L. Li, X. Hu, X. Yu, L. Zhao, Beijing Institute of Technology (China)
- 6834 14 **Design of objective lenses to extend the depth of field based on wavefront coding** [6834-62]
T. Zhao, Z. Ye, W. Zhang, W. Huang, F. Yu, Zhejiang Univ. (China)
- 6834 15 **Strehl ratio analysis for the wavefront coding system** [6834-68]
W. Zhang, Z. Ye, T. Zhao, F. Yu, Zhejiang Univ. (China)

SESSION 10 OPTICAL MEASUREMENT

- 6834 16 **A generalized temporal phase unwrapping algorithm (Invited Paper)** [6834-72]
J. Tian, X. Peng, X. Zhao, Shenzhen Univ. (China)
- 6834 17 **Simultaneous defect inspection on the surface and in the interior of bare wafers using a simple knife-edge test** [6834-04]
J. H. Lee, Kongju National Univ. (South Korea); Y. Kim, Mirae Technology (South Korea); J. Kim, HanTech Co. Ltd. (South Korea); Y. Yoo, Korea Institute of Machinery & Materials (South Korea)
- 6834 18 **Research of light reflex surface defects detection technology** [6834-118]
J. Tian, Y. Yao, Y. Sun, W. Shi, X. Zhao, X. Yu, Harbin Institute of Technology (China)

SESSION 11 OPTICAL SYSTEM ANALYSIS AND OPTIMIZATION

- 6834 19 **Optimization of sampled imaging system with baseband response squeeze model (Invited Paper)** [6834-145]
H. Yang, K. Chen, X. Huang, Q. He, G. Jin, Tsinghua Univ. (China)
- 6834 1A **Development in local and global optimization methods** [6834-91]
Q. Ding, H. Liu, Luoyang Institute of Electro-Optical Equipment of AVIC (China)
- 6834 1B **Analysis of infrared radiation from optical window with graded temperature distribution** [6834-154]
X. Li, Z. Cen, Q. Liu, Zhejiang Univ. (China)

- 6834 1C **Using Monte-Carlo method for evaluating the imaging through a disturbed medium with random distribution** [6834-53]
Q. Liu, X. Li, Z. Cen, S. Deng, Zhejiang Univ. (China)
- 6834 1D **Comparison of ray-tracing methods in self-adaptive grid for inhomogeneous medium** [6834-15]
S. T. Deng, X. T. Li, Z. F. Cen, Q. S. Liu, Zhejiang Univ. (China)

SESSION 12 OPTICAL TESTING AND SYSTEM ALIGNMENT

- 6834 1E **Electrically calibrated pyroelectric detector for high-accuracy calibration of UV radiation** [6834-94]
X. Shao, Shanghai Institute of Technical Physics (China) and Graduate School of the Chinese Academy of Sciences (China); J. Ding, Y. Yu, J. Fang, Shanghai Institute of Technical Physics (China)
- 6834 1G **Novel method based on DDE technology for computer-aided alignment** [6834-129]
Y. Huang, L. Li, Beijing Institute of Technology (China)
- 6834 1H **Research on measurement of lens centering errors based on image processing** [6834-98]
Y. Lin, G. Dong, Y. Huang, Y. Niu, Tianjin Univ. (China)

POSTER SESSION

- 6834 1Q **Optical design of a synthetic aperture ladar antenna system** [6834-02]
C. Cao, X. Zeng, X. Zhao, H. Liu, X. Man, Xidian Univ. (China)
- 6834 1R **Design of a wide field of view infrared scene projector** [6834-06]
Z. Jiang, L. Li, Y. Huang, Beijing Institute of Technology (China)
- 6834 1S **Improved first Rayleigh Sommerfeld method for investigating microlens array with long focal depth and small f-number** [6834-07]
J. Liu, F. Sun, C. Hu, G. Zhang, Y. Liu, Beijing Jiaotong Univ. (China)
- 6834 1U **Algorithm realization of median filter in multiple environments testing conditions for low-level-light sight devices measurement system** [6834-10]
Y. Gao, S. Tian, NanYang Institute of Technology (China) and NanJing Univ. of Science and Technology (China); B. Chang, Y. Qiu, NanYang Institute of Technology (China); J. Qiao, NanYang Institute of Technology (China) and NanJing Univ. of Science and Technology (China)
- 6834 1V **Multi-alkali photocathode thermal performance analysis of image intensifier based on low-high temperature environment testing conditions** [6834-11]
Y. Gao, S. Tian, NanYang Institute of Technology (China) and NanJing Univ. of Science and Technology (China); B. Chang, Y. Qiu, NanYang Institute of Technology (China); J. Qiao, NanYang Institute of Technology (China) and NanJing Univ. of Science and Technology (China)

- 6834 1W **Influence of temperature on fractal dimension of dynamic scattered light intensity signal of ultrafine particles** [6834-13]
J. Shen, B. Tan, Q. Ding, S. Yang, Shandong Univ. of Technology (China)
- 6834 1Y **Effect of radius mismatch on performance of segmented telescopic systems** [6834-17]
D. Cheng, Y. Wang, M. M. Talha, J. Chang, Beijing Institute of Technology (China); H. Hua, College of Optical Sciences, Univ. of Arizona (USA)
- 6834 1Z **Extrapolation method to extend the dynamic range of the Shack-Hartmann wave-front sensor** [6834-20]
H. Li, H. Song, Institute of Optics and Electronics (China) and Graduate School of Chinese Academy of Sciences (China); X. Rao, C. Rao, J. Yang, Institute of Optics and Electronics (China)
- 6834 20 **Application of a white-light interferometric measuring system as co-phasing the segmented primary mirrors of the high-aperture telescope** [6834-22]
H. Song, H. Li, Institute of Optics and Electronics (China) and Graduate School of Chinese Academy of Sciences (China); H. Xian, Institute of Optics and Electronics (China); J. Huang, S. Wang, Institute of Optics and Electronics (China) and Graduate School of Chinese Academy of Sciences (China); W. Jiang, Institute of Optics and Electronics (China)
- 6834 21 **Method for calculating the center position of collimated laser beam spots** [6834-26]
G. Wu, L. Wu, Y. Cang, Xi'an Institute of Optics and Precision Mechanics (China) and Graduate School of the Chinese Academy of Sciences (China); L. Chen, Xi'an Institute of Optics and Precision Mechanics (China)
- 6834 22 **Particle size measurement system of the aerosol time-of-flight mass spectrometer optimization study** [6834-27]
W. Zhao, X. Gu, L. Hao, M. Huang, H. Zheng, L. Fang, W. Zhang, Anhui Institute of Optics and Fine Mechanics (China)
- 6834 23 **Dark point algorithm: a new method to test periodic structures of optical instruments** [6834-31]
D. Cai, Y. Song, Univ. of Science and Technology of China (China)

Part Two

- 6834 24 **Spherical aberration correction of Gaussian beam** [6834-32]
Q. Li, Xidian Univ. (China)
- 6834 25 **Measurement of self-organization pattern in dielectric barrier discharge by a special photoelectronic detection system** [6834-33]
Z. Zhao, L. Dong, Y. Qi, Y. He, Y. Li, Hebei Univ. (China)
- 6834 27 **Study on the photo-electrical characteristics of different patterns in dielectric barrier discharge by using photoelectricity method** [6834-36]
Y. Qi, L. Dong, Z. Zhao, Y. Li, Hebei Univ. (China)
- 6834 28 **Improvement in design of panoramic annular lens using cemented lenses** [6834-37]
S. Niu, J. Bai, X. Hou, G. Yang, Zhejiang Univ. (China)

- 6834 2A **Simulation of the phase-shift and anti-vibration in wavefront time-domain algorithm** [6834-40]
L. Tang, Q. Hao, Q. Zhu, Beijing Institute of Technology (China)
- 6834 2B **Athermalization for infrared dual field-of-view optical system** [6834-42]
C. Yang, S. Li, Huazhong Institute of Electro-Optics (China)
- 6834 2D **Comparison of signals under top-hat and Gaussian beam excitations in surface thermal lens technique** [6834-49]
M. Liu, Institute of Optics and Electronics (China) and Graduate School of Chinese Academy of Sciences (China); B. Li, Institute of Optics and Electronics (China); H. Hao, Institute of Optics and Electronics (China) and Graduate School of Chinese Academy of Sciences (China)
- 6834 2E **Microscope auto-focusing system with the self-adaptive mountain-climbing search method based on PC control** [6834-50]
L. Xu, Z. Ye, J. Wu, X. Yan, F. Yu, Zhejiang Univ. (China)
- 6834 2F **Modulation transfer function measurement of charge-coupled devices using frequency-variable fringe patterns** [6834-54]
L. Zhao, H. Feng, Z. Xu, Zhejiang Univ. (China)
- 6834 2G **Analysis of resolution criterion and aberrations for Fizeau interferometer** [6834-55]
S. Wang, Institute of Optics and Electronics (China) and Graduate School of the Chinese Academy of Sciences (China); C. Rao, W. Jiang, Institute of Optics and Electronics (China)
- 6834 2I **Observation of aerosol with a compact lidar over Hefei, China** [6834-59]
Z. Liu, J. Liu, W. Liu, X. Zhao, S. Huang, W. Feng, F. Xiao, Anhui Institute of Optics and Fine Mechanics (China)
- 6834 2J **The effect of beam incident angles on cube corner retro-reflector measurement accuracy** [6834-63]
J. Ouyang, Henan Polytechnic Univ. (China); W. Liu, X. Qu, Tianjin Univ. (China); Y. Yan, Henan Polytechnic Univ. (China)
- 6834 2K **The optimal design of TIR lens for improving LED illumination uniformity and efficiency** [6834-67]
Y. Zhen, Z. Jia, Xian Shiyou Univ. (China); W. Zhang, Zhejiang Univ. (China)
- 6834 2L **Design of double refractive pattern recognition system for optical low pass filter** [6834-69]
X. Li, S. Jin, L. Wang, China Jiliang Univ. (China)
- 6834 2M **A subpixel localization method based on edge diffraction** [6834-71]
Y. Wang, M. Peng, X. Cheng, Foshan Univ. (China)
- 6834 2N **Evaluation of the sphericity measurement uncertainty for the fiber point diffraction interferometer** [6834-74]
L. Chen, D. Sha, Beijing Institute of Technology (China)

- 6834 2O **A new method of evaluating counting efficiency based on signal amplitude response function** [6834-75]
J. Yang, F. Gu, G. Peng, B. Bian, J. Lu, Nanjing Univ. of Science and Technology (China)
- 6834 2P **Research on design of optimum phase mask for wave-front coded imaging system** [6834-80]
H. Zhao, H. Feng, Q. Li, Zhejiang Univ. (China)
- 6834 2R **Preliminary analysis and experiment of thermal influence on a large-aperture mirror** [6834-82]
W. Hu, Beijing Institute of Technology (China); P. Xu, Beijing Institute of Space Mechanics and Electronics (China); H. Zhang, L. Zhao, G. Bian, X. Yu, X. Hu, Beijing Institute of Technology (China)
- 6834 2S **Research of the grid computing system applied in optical simulation** [6834-85]
W. Jin, Y. Wang, Q. Liu, Z. Cen, X. Li, Y. Lin, Zhejiang Univ. (China)
- 6834 2U **Application of MATLAB in optical alignment** [6834-89]
S. Xiao, Y. Tang, Changchun Univ. of Science and Technology (China)
- 6834 2V **The wavefront aberration analysis and testing accuracy evaluation for the large aberration aspheric system based on the best fit sphere** [6834-93]
J. Weng, Y. Yang, D. Liu, Y. Shen, Y. Zhuo, Zhejiang Univ. (China)
- 6834 2W **A robust and efficient point matching method for stereovision measurement using dynamic programming** [6834-97]
P. Sun, N. Lu, Beijing Information Science and Technology Univ. (China)
- 6834 2X **Highly precise nonlinear error calibrating system based on Fabry-Perot interferometer** [6834-99]
J. Ma, Y. Li, C. Yin, Tsinghua Univ. (China)
- 6834 2Y **Experimental study on Zeeman-birefringence dual-frequency laser interferometer with mid-frequency difference** [6834-100]
Y. Zhang, Y. Li, S. Zhang, Tsinghua Univ. (China)
- 6834 2Z **Measurement of target deformation under laser shock with optical beam shading technique** [6834-101]
G. Dai, Z.-H. Shen, J. Lu, X. W. Ni, Nanjing Univ. of Science and Technology (China)
- 6834 30 **CCD-based on-line thickness measurement system for calender** [6834-103]
L. Guo, Tsinghua Univ. (China); Y. Fan, G. Zhang, Tianjin Univ. (China); K. Chen, Tsinghua Univ. (China)
- 6834 31 **A digital optical autocollimation method for measuring 2D small angle** [6834-105]
L. Ma, B. Yan, N. Lu, Beijing Institute of Machinery (China)
- 6834 32 **A specially designed optical system for measurement of the characteristic of square super-lattice pattern in DBD** [6834-107]
H. Zhao, L. Dong, W. Xie, W. Fan, Hebei Univ. (China)

- 6834 33 **An optical method of online measurement for the thickness of thin films** [6834-108]
M. Song, Dalian Nationality Univ. (China); Y. Zheng, Liaoning Normal Univ. (China) Y. Lu,
Y. Qu, Dalian Nationality Univ. (China)
- 6834 34 **Research on field correctors of the infrared space optical remote sensor** [6834-111]
B. Hui, J. Li, Shenzhen Univ. (China); Y. Pei, Shanghai Institute of Technical Physics (China);
Q. Wu, Shenzhen Univ. (China)
- 6834 35 **Key techniques in an absolute measurement method of spherical lens** [6834-113]
S. Wu, T. Zhou, D. Sha, J. Lin, L. Chen, Beijing Institute of Technology (China)
- 6834 37 **Research on color encoding structured light 3D measurement technology** [6834-116]
Y. Fu, G. Liu, Beijing Institute of Machinery (China)
- 6834 38 **Simulation of atmospheric turbulence layers with phase screens by JAVA** [6834-117]
X. Zhang, W. Chen, X. Yu, J. Yan, Beijing Institute of Technology (China)
- 6834 3A **A novel method of lens initial structure selection: study on structures-aperture relationship of finite image distance achromatic spherical microscope objective with larger numerical aperture** [6834-128]
N. Liu, Y. Zhang, F. Fang, Tianjin Univ. (China)
- 6834 3B **Design of an FT-NIR spectrometer for online quality analysis of traditional Chinese medicine manufacturing process** [6834-130]
R. Zhu, L. Wu, S. Wang, L. Ye, Z. Ding, Zhejiang Univ. (China)
- 6834 3C **A high-accuracy dual-channel method of measurement on visible light transmittance of telescope system** [6834-132]
J. Lu, Y. Xiang, L. Wu, K. Yin, Changchun Univ. of Science and Technology (China)
- 6834 3D **Study of CAD-based laser guiding measurement technology** [6834-137]
Y. Yan, J. Ouyang, Henan Polytechnic Univ. (China); W. Liu, Tianjin Univ. (China); F. Xia,
Henan Polytechnic Univ. (China)
- 6834 3E **Specular surface measurement by using a moving diffusive structured light source**
[6834-139]
H. Guo, T. Tao, Shanghai Univ. (China)
- 6834 3F **Infrared telephoto lens design of hybrid optoelectronic joint transform correlator** [6834-140]
F. Guo, H. Wang, L. Li, N. Yin, W. Wang, Changchun Univ. of Science and Technology
(China)
- 6834 3G **Information entropy characteristic of the light scattering signal amplitude distribution of aerosols** [6834-141]
F. Gu, J. Yang, B. Bian, A. He, Nanjing Univ. of Science and Technology (China)
- 6834 3H **Optical measurement of discharge pattern in dielectric barrier discharge system**
[6834-144]
W. Liu, L. Dong, H. Wang, Y. He, Hebei Univ. (China)

- 6834 3I **Michelson interferometer in a 2D photonic crystal utilizing self-collimation effect** [6834-146]
X. Chen, Minjiang Univ. (China); Y. Qiu, Y. Wang, Fujian Normal Univ. (China); N. Lin, G. Lin, Minjiang Univ. (China); H. Hong, B. Ni, Fujian Normal Univ. (China)
- 6834 3J **Optical fiber method for measuring small plane flatness error** [6834-147]
S. Jin, Y. Lv, Q. S. Chen, Beijing Institute of Machinery (China)
- 6834 3K **Area testing study of arbitrary shape plane object based on CCD matrix** [6834-148]
S. Jiang, D. Liu, W. Wang, Changchun Univ. of Science and Technology (China)
- 6834 3L **Equipment for 2D profile measuring of aspheric microscope condenser in mass production** [6834-149]
X. Cheng, J. Ma, Tsinghua Univ. (China); Y. Zhang, Motic China Group Co., Ltd. (China)
- 6834 3M **A novel optical tweezers system** [6834-151]
X. Feng, J. Fang, T. Zhu, C. Zhao, J. Fan, Soochow Univ. (China)
- 6834 3N **Optical design of free-form bicycle lamp** [6834-152]
C. Tian, Z. Cen, S. Deng, J. Wang, Zhejiang Univ. (China)
- 6834 3P **Research and design of an optical system of biochemical analyzer based on the narrow-band pass filter** [6834-160]
Z. Xiao, K. Chen, Guilin Univ. of Electronic Technology (China)
- 6834 3R **The influence of high-order dispersion on femesecond solitons** [6834-165]
Z. Wang, Z. Li, Y. Liu, J. Chen, Z. Li, Yanshan Univ. (China)
- 6834 3S **Distributed optical fiber sensor for multi-point temperature measurement** [6834-166]
H. Wang, Z. Wang, Z. Bai, Z. Li, Yanshan Univ. (China)
- 6834 3U **Error analysis for integrating sphere of color measuring system** [6834-169]
S. Jin, K. Yuan, China Jiliang Univ. (China)
- 6834 3V **Analytical method of genetic algorithm in fiber grating sensing system with transverse uniform stress** [6834-170]
Z. Li, W. Yin, H. Wang, Z. Zhou, Yanshan Univ. (China)
- 6834 3W **Technology of wavelength tuning based on refractive optical lever and its application in optical spectrum analysers** [6834-171]
Y. Qiu, H. Xu, Y. Gao, Fujian Normal Univ. (China)
- 6834 3X **Scene simulation optics in testing of dual-field angle infrared imagers** [6834-173]
Y. Zheng, J. Gao, J. Wang, H. Chen, Xi'an Institute of Applied Optics (China)
- 6834 3Y **Design of infrared zoom system with rotating lens group** [6834-174]
Y. Li, C. Yang, S. Li, Huazhong Institute of Electro-Optics (China)
- 6834 40 **Research on a system and method of automated whole-field measurement of optical glass stress** [6834-181]
L. Zhang, Y. Tang, T. Bai, Beijing Institute of Technology (China)

- 6834 42 **A prototype system for high precision 3D measurement based on grating method**
[6834-184]
Z. Li, Y. Shi, C. Wang, G. Zhou, D. Qin, Huazhong Univ. of Science and Technology (China)
- 6834 43 **A novel ellipsometer for measuring thickness of oxide layer on the surface of silicon sphere**
[6834-106]
J. Zhang, Y. Li, Tsinghua Univ. (China)
- 6834 46 **Simulation of multi-reentrant two-mirror ring cavity lasers** [6834-190]
F.-H. Tseng, S.-K. Liu, National Kaohsiung Univ. of Applied Sciences (Taiwan, China)

Author Index

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- 6 Interferometry in Optical Testing
Qun Hao, Beijing Institute of Technology (China)
- 7 Testing for Aspheric Surfaces
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- 9 Wavefront Sensing and Coding
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- 10 Optical Measurement
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Yifan Huang, Beijing Institute of Technology (China)
- 12 Optical Testing and System Alignment
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Introduction

Photonics Asia met in Beijing, China during the week of 11–15 of November 2007.

By all indications it was a rousing success. Photonics Asia opened the conference with a memorable opening ceremony with SPIE leaders introduced from throughout the world, followed by four Plenary speeches:

- Solid State Lighting
by Jinmin Li of the Institute of Semiconductors of the Chinese Academy of Science
- The National Ignition Facility also known as the World's Largest Optical System
by Christopher Stolz of Lawrence Livermore National Laboratory in the USA
- A Brief Introduction to Biophotonics and Selected Applications
by Arthur Chiou of the National Yang-Ming University in Japan
- Terahertz Wave Photonics in Gas and its Spectroscopic Applications
by X.-C. Zhang of the Rensselaer Polytechnic Institute in the USA

Photonics Asia started as a new conference in 2002 in Shanghai, followed by a second conference held also in Beijing in 2004. This 3rd Photonics Asia (2007) was managed and sponsored by SPIE and the Chinese Optical Society (COS). Many corporation leaders participated in the conference.

Attendance at the conference has been growing reaching a total over the entire conference of 1269 papers, 615 posters, and 127 invited talks, including a strong international presence this year. The conference topics within the Optical Design and Testing conference span a wide variety of fields including

- Astronomical and space optics
- Wavefront sensing and coding
- Novel system design
- Illumination system design
- Compact optics
- Head-mounted display design
- Nano- and Micro-optics
- Optical system analysis and optimization
- Optical Measurement
- Optical testing and system alignment
- Testing for aspheric surfaces
- Interferometry in optical testing

It was a pleasure working with SPIE and Photonics Asia 2007, and we look forward to seeing you in 2009!

Yongtian Wang
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